

# MBN1000E33E2

Preliminary Specification

Silicon N-channel IGBT 3300V E2 version

## FEATURES

- \* Soft switching behavior & low conduction loss:  
Soft low-injection punch-through High conductivity IGBT.
- \* Low driving power due to low input capacitance MOS gate.
- \* Low noise recovery: Ultra soft fast recovery diode.
- \* High thermal fatigue durability:  
( $\Delta T_c=70K$ ,  $N>30,000$ cycles)  
AlSiC base-plate/AlN substrate

## ABSOLUTE MAXIMUM RATINGS ( $T_c=25^\circ\text{C}$ )

Item	Symbol	Unit	MBN1000E33E2
Collector Emitter Voltage	$V_{CES}$	V	3,300
Gate Emitter Voltage	$V_{GES}$	V	$\pm 20$
Collector Current	DC	$I_C$	1,000 ( $T_c=95^\circ\text{C}$ )
	1ms	$I_{CP}$	
Forward Current	DC	$I_F$	1,000
	1ms	$I_{FM}$	2,000
Junction Temperature	$T_j$	$^\circ\text{C}$	-40 ~ +150
Storage Temperature	$T_{stg}$	$^\circ\text{C}$	-50 ~ +125
Isolation Voltage	$V_{ISO}$	$V_{RMS}$	6,000(AC 1 minute)
Screw Torque	Terminals (M4/M8)	-	2/15 (1)
	Mounting (M6)	-	6 (2)

Notes: (1) Recommended Value  $1.8\pm 0.2/15^{+0}_{-3}$  N·m(2) Recommended Value  $5.5\pm 0.5$  N·m

## ELECTRICAL CHARACTERISTICS

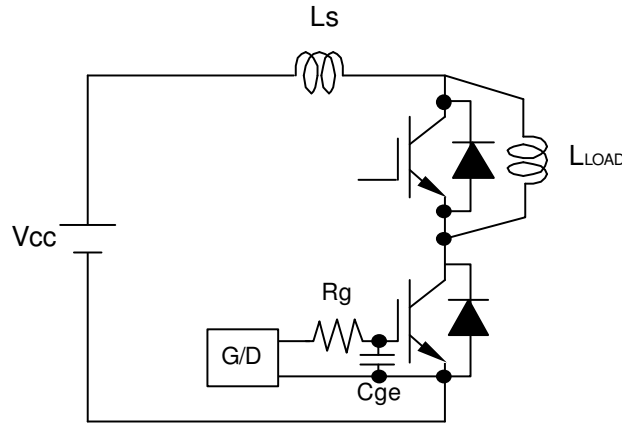
Item	Symbol	Unit	Min.	Typ.	Max.	Test Conditions	
Collector Emitter Cut-Off Current	$I_{CES}$	mA	-	-	8	$V_{CE}=3,300\text{V}$ , $V_{GE}=0\text{V}$ , $T_j=25^\circ\text{C}$	
			-	14	40	$V_{CE}=3,300\text{V}$ , $V_{GE}=0\text{V}$ , $T_j=125^\circ\text{C}$	
Gate Emitter Leakage Current	$I_{GES}$	nA	-500	-	+500	$V_{GE}=\pm 20\text{V}$ , $V_{CE}=0\text{V}$ , $T_j=25^\circ\text{C}$	
Collector Emitter Saturation Voltage	$V_{CE(sat)}$	V	tbd	2.95	tbd	$I_C=1,000\text{A}$ , $V_{GE}=15\text{V}$ , $T_j=125^\circ\text{C}$	
			-	3.10	-	$I_C=1,000\text{A}$ , $V_{GE}=15\text{V}$ , $T_j=150^\circ\text{C}$	
Gate Emitter Threshold Voltage	$V_{GE(TO)}$	V	5.5	6.5	7.5	$V_{CE}=10\text{V}$ , $I_C=1,000\text{mA}$ , $T_j=25^\circ\text{C}$	
Input Capacitance	$C_{ies}$	nF	-	130	-	$V_{CE}=10\text{V}$ , $V_{GE}=0\text{V}$ , $f=100\text{kHz}$ , $T_j=25^\circ\text{C}$	
Internal Gate Resistance	$R_{ge}$	$\Omega$	-	1.9	-	$V_{CE}=10\text{V}$ , $V_{GE}=0\text{V}$ , $f=100\text{kHz}$ , $T_j=25^\circ\text{C}$	
Switching Times	Rise Time	$t_r$	tbd	2.5	tbd	$V_{CC}=1,650\text{V}$ , $I_C=1,000\text{A}$ $L=120\text{nH}$ $R_G=3.9\Omega/3.9\Omega$ , $C_{GE}=220\text{nF}$ (3)	
	Turn On Time	$t_{on}$	tbd	3.6	tbd		
	Fall Time	$t_f$	tbd	1.8	tbd		
	Turn Off Time	$t_{off}$	tbd	4.1	tbd		
Peak Forward Voltage Drop	$V_{FM}$	V	tbd	2.5	tbd	$I_F=1,000\text{A}$ , $V_{GE}=0\text{V}$ , $T_j=125^\circ\text{C}$	
			-	2.5	-	$I_F=1,000\text{A}$ , $V_{GE}=0\text{V}$ , $T_j=150^\circ\text{C}$	
Reverse Recovery Time	$t_{rr}$	$\mu\text{s}$	-	0.9	tbd	$V_{CC}=1,650\text{V}$ , $I_F=1,000\text{A}$ , $L=120\text{nH}$ $T_j=125^\circ\text{C}$	
Turn On Loss	$E_{on(10\%)}$	J/P	-	2.5	tbd	$T_j=125^\circ\text{C}$	
	$E_{on(full)}$		-	2.7	-		$T_j=150^\circ\text{C}$
Turn Off Loss	$E_{off(10\%)}$	J/P	-	1.5	tbd	$V_{CC}=1,650\text{V}$ , $I_C=I_F=1,000\text{A}$ , $L=120\text{nH}$ , $R_G=3.9\Omega/3.9\Omega$ , $C_{GE}=220\text{nF}$ (3) $V_{GE}=\pm 15\text{V}$	
	$E_{off(full)}$		-	1.6	-		$T_j=125^\circ\text{C}$
	-		-	tbd	-		$T_j=150^\circ\text{C}$
	-		-	tbd	-		$T_j=150^\circ\text{C}$
Reverse Recovery Loss	$E_{rr(10\%)}$	J/P	-	1.1	tbd	$T_j=125^\circ\text{C}$	
	$E_{rr(full)}$		-	1.3	-		$T_j=150^\circ\text{C}$

Notes:(3)  $R_G$  and  $C_{GE}$  value are the test condition's value for evaluation of the switching times, not recommended value.Please, determine the suitable  $R_G$  value after the measurement of switching waveforms (overshoot voltage, etc.) with appliance mounted.

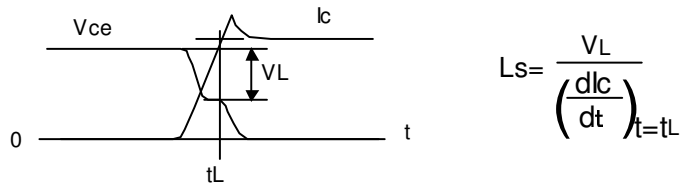
Stray inductance module		LsCE	nH	-	18	-	
Thermal Impedance	IGBT	Rth(j-c)	K/W	-	-	0.012	Junction to case
	FWD	Rth(j-c)	K/W	-	-	0.024	
Contact Thermal Impedance		Rth(c-f)	K/W	-	0.008	-	Case to fin

- \* Please contact our representatives at order.
- \* For improvement, specifications are subject to change without notice.
- \* For actual application, please confirm this spec sheet is the newest revision.

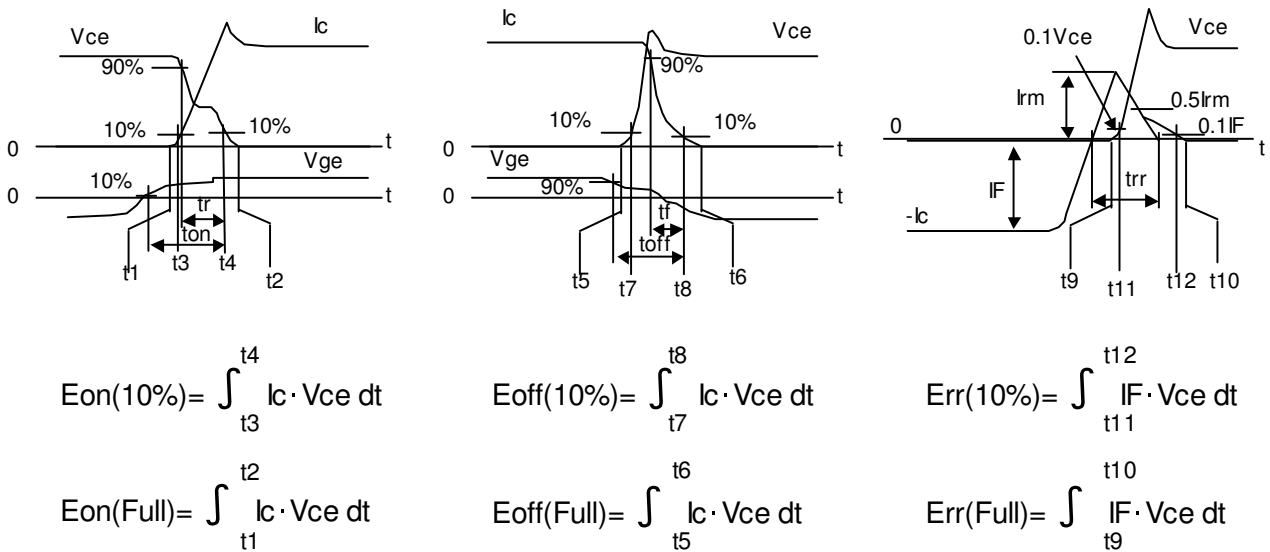
**DEFINITION OF TEST CIRCUIT**



**Fig.1 Switching test circuit**

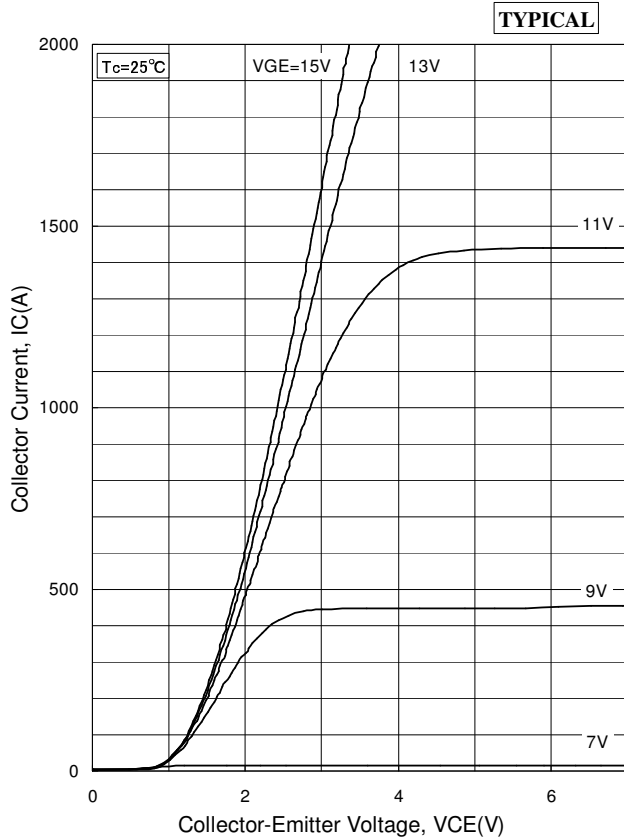


**Fig.2 Definition of Ls**

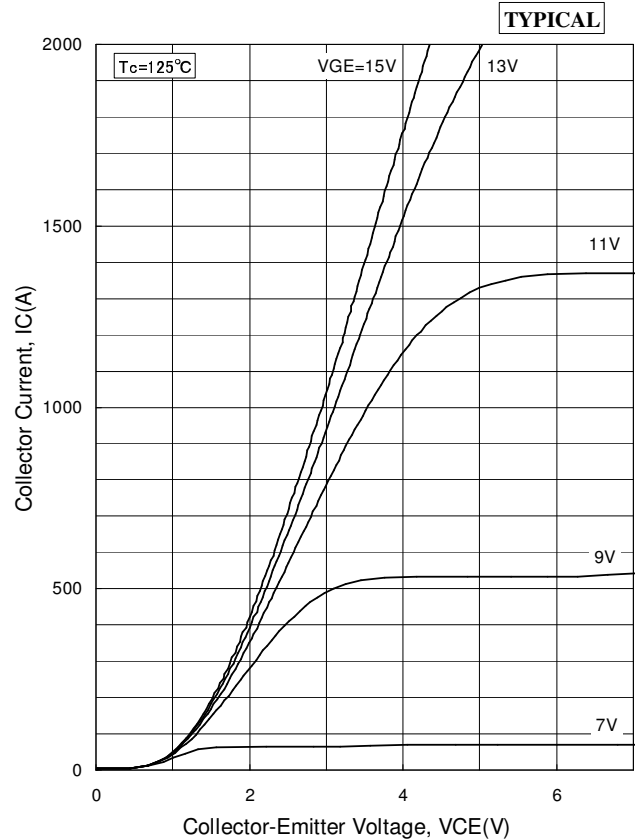


**Fig.3 Definition of switching loss**

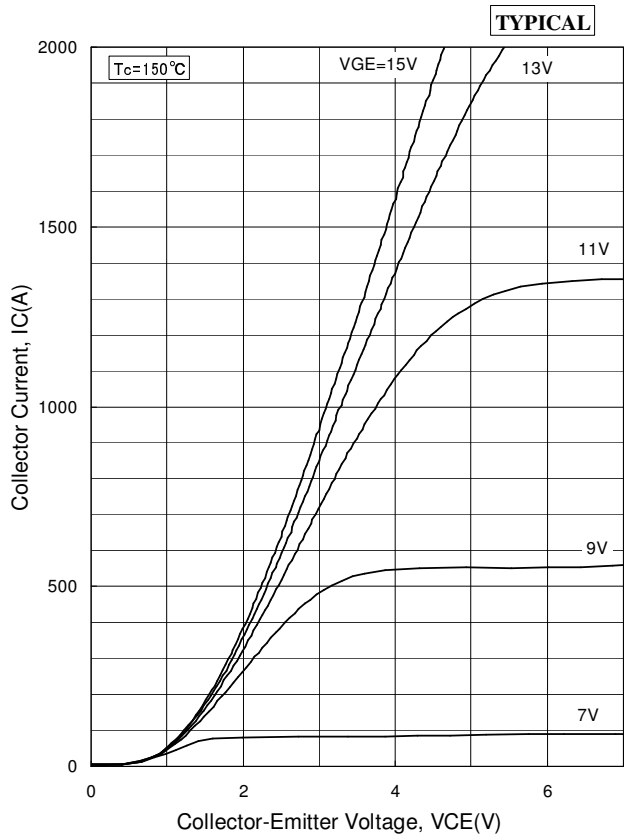
1. STATIC CHARACTERISTICS



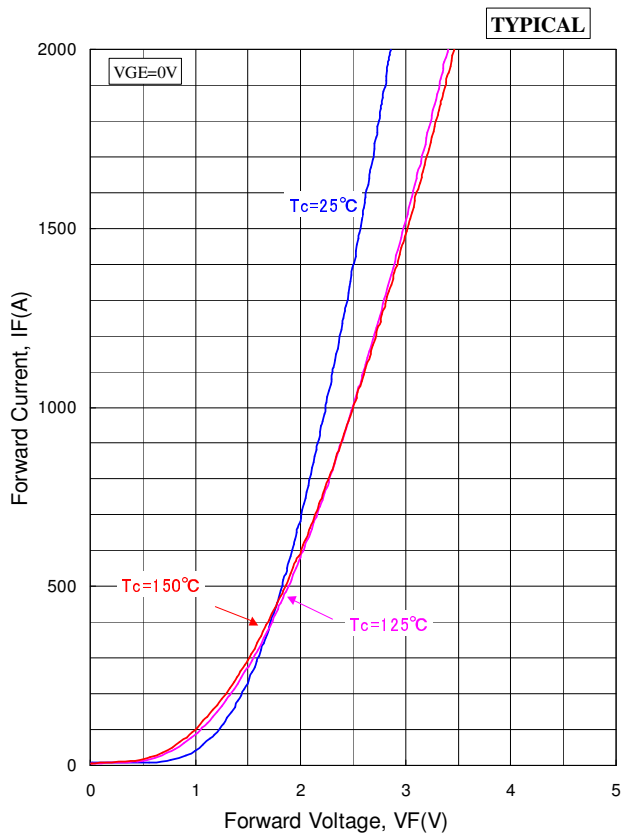
Collector Current vs. Collector to Emitter Voltage



Collector Current vs. Collector to Emitter Voltage

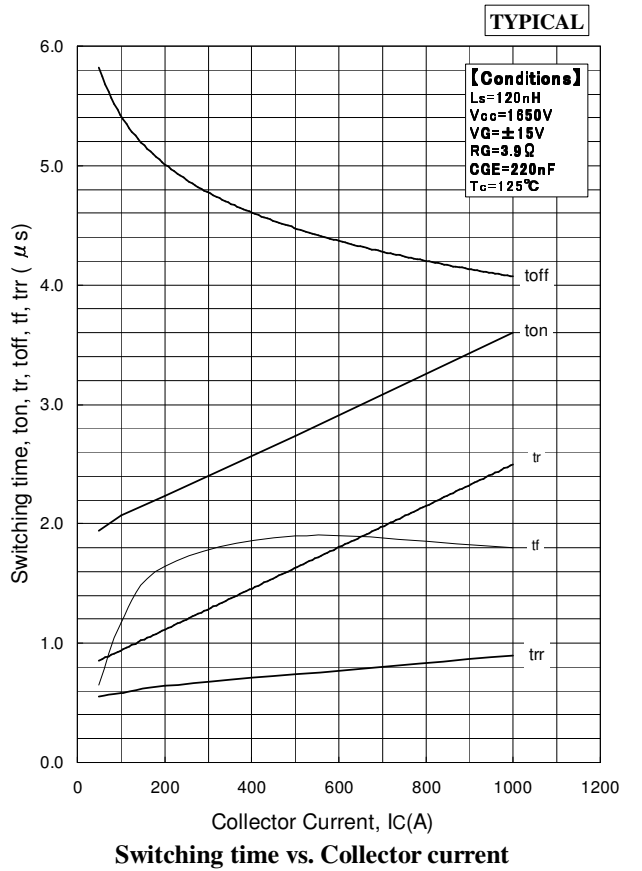
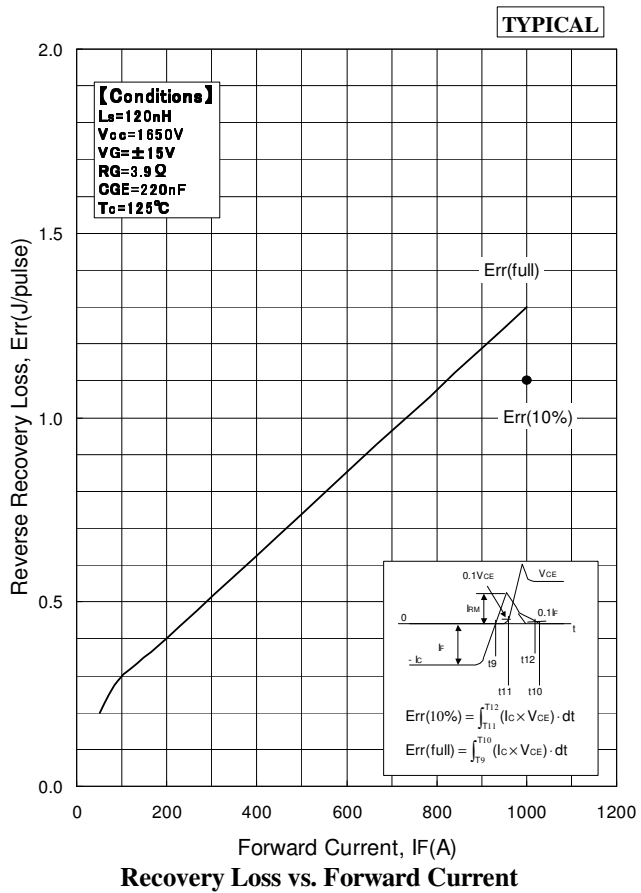
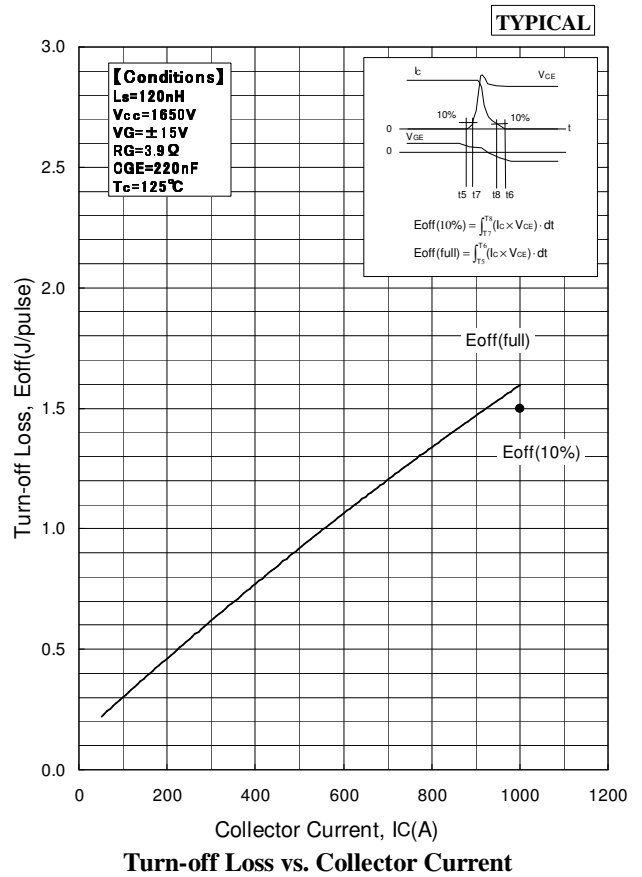
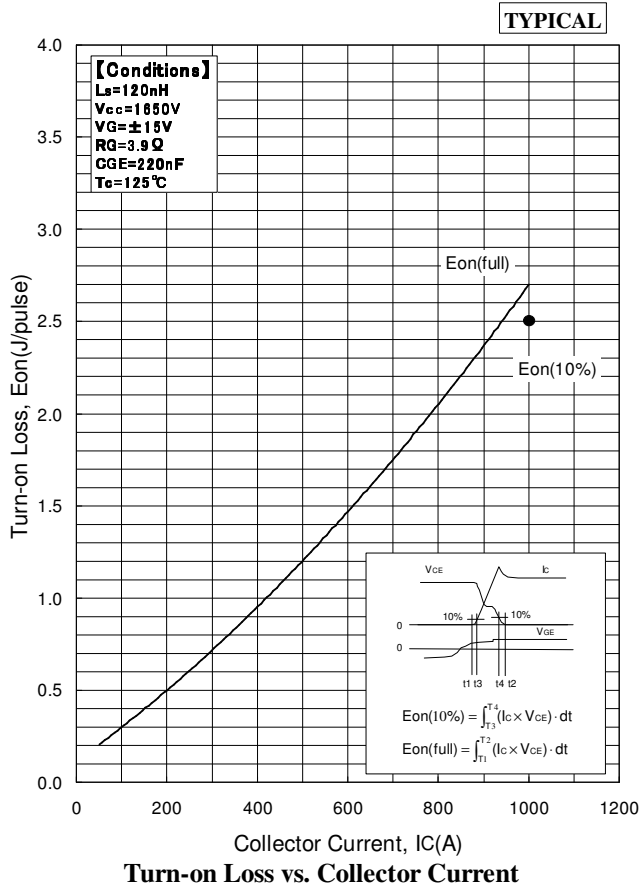


Collector Current vs. Collector to Emitter Voltage



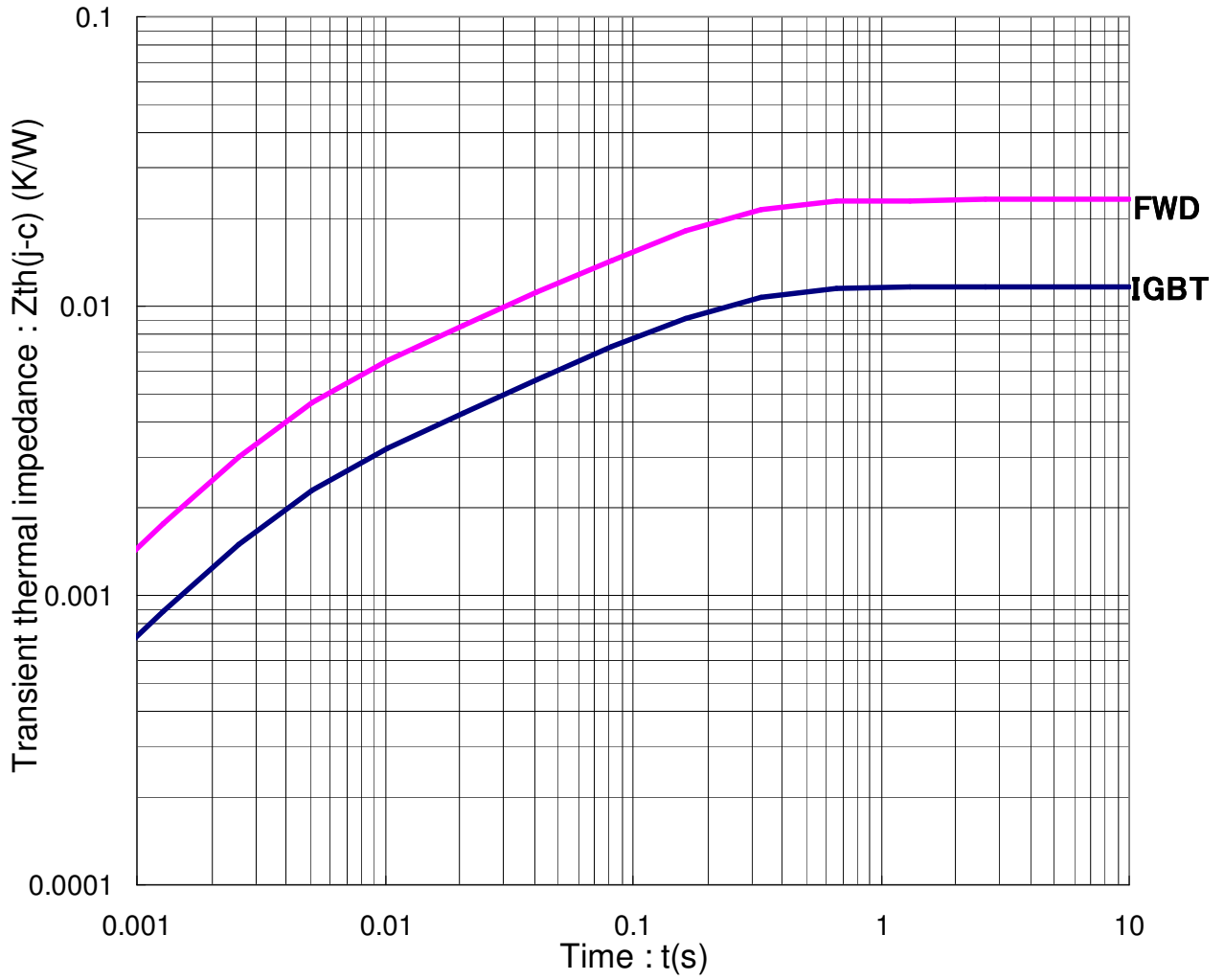
Forward Voltage of free-wheeling diode

2. DYNAMIC CHARACTERISTICS



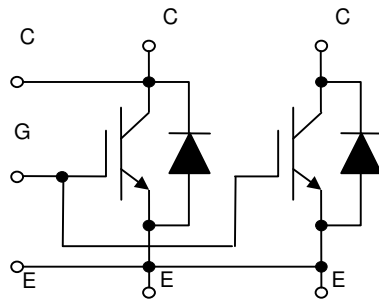
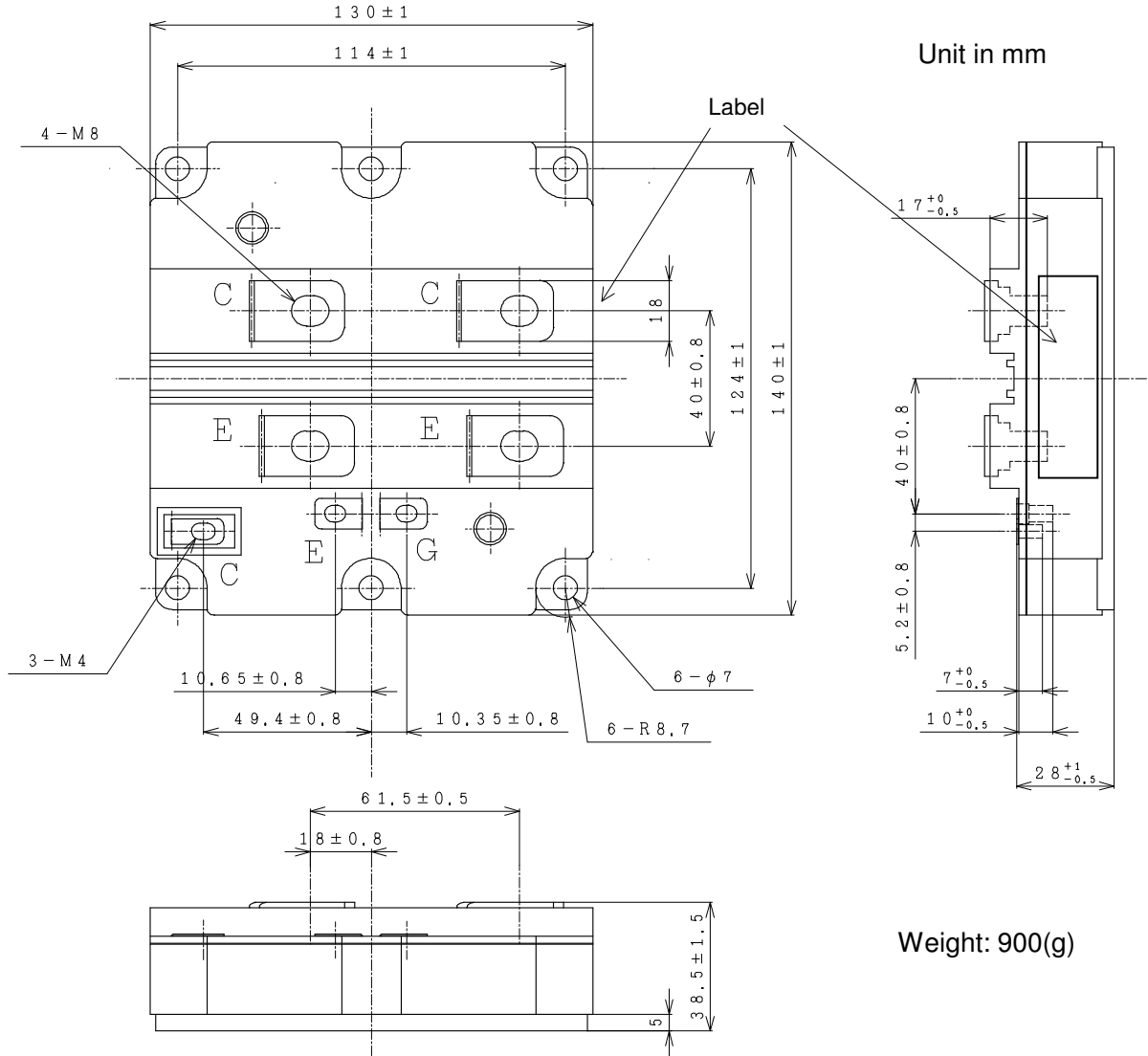
### 3. TRANSIENT THERMAL IMPEDANCE

**Maximum**



### Transient Thermal Impedance Curve

4. OUTLINE DRAWINGS



Circuit diagram

5. Negative environmental impact material

Please note the following negative environmental impact materials are contained in the product in order to keep product characteristic and reliability level.

Material	Contained part
Lead (Pb) and its compounds	Solder
Arsenic and its compounds	Si chip

# HITACHI POWER SEMICONDUCTORS

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